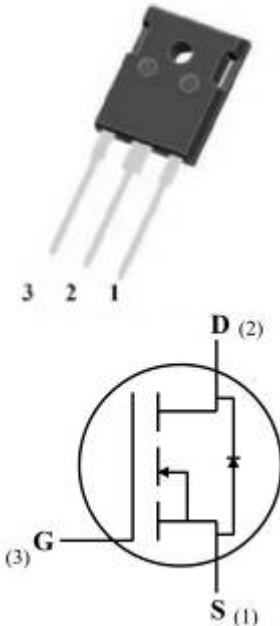


## Silicon Carbide Power MOSFET (N-Channel Enhancement)

$V_{DS}$	1200V
$I_D$ (25°C)	68A
$R_{DS(on)}$	30mΩ



### Features

- High speed switching
- Essentially no switching losses
- Reduction of heat sink requirements
- Maximum working temperature at 175 °C
- High blocking voltage
- Fast Intrinsic diode with low recovery current
- High-frequency operation
- Halogen free, RoHS compliant

### Typical Applications

Typical applications are in power factor correction(PFC), solar inverter, uninterruptible power supply, motor drives, photovoltaic inverter, electric car and charger.

### Mechanical Data

- **Package:** TO-247AB
- **Terminals:** Tin plated leads
- **Polarity:** As marked

### ■Maximum Ratings (T<sub>c</sub>=25°C Unless otherwise specified)

PARAMETER	SYMBOL	UNIT	VALUE	TEST CONDITIONS	NOTE
Device marking code				D212030NCTG2	
Drain source voltage @ T <sub>j</sub> =25°C	$V_{DS,max}$	V	1200	$V_{GS}=0\text{ V}, I_D=100\mu\text{A}$	
Gate source voltage @ T <sub>j</sub> =25°C	$V_{GS,max}$	V	-8/+20	Absolute maximum values	
Gate source voltage @ T <sub>j</sub> =25°C	$V_{GS,op}$	V	-5/+18	Recommended operational values	
Continuous drain current @ T <sub>c</sub> =25°C	$I_D$	A	68	$V_{GS}=18\text{V}, T_c=25^\circ\text{C}$	Fig.17
Continuous drain current @ T <sub>c</sub> =100°C			50	$V_{GS}=18\text{V}, T_c=100^\circ\text{C}$	
Pulsed drain current	$I_{D(pulsed)}$	A	100	Pulse width t <sub>p</sub> limited by T <sub>j,max</sub>	
Power Dissipation	$P_{TOT}$	W	333	$T_c=25^\circ\text{C}, T_j = 175^\circ\text{C}$	Fig.16
Power Dissipation			165	$T_c=100^\circ\text{C}, T_j = 175^\circ\text{C}$	
Operating junction and Storage temperature range	T <sub>j</sub> , T <sub>stg</sub>	°C	-55 to +175		
Soldering temperature	T <sub>L</sub>	°C	260	1.6mm (0.063") from case for 10s	
Mounting torque	T <sub>M</sub>	Nm	0.6	M3 screw Maximum of mounting process: 3	


**■Static Electrical Characteristics** (Tc=25°C unless otherwise specified )

PARAMETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Gate threshold voltage	V <sub>GS(th)</sub>	V	2.0	3.7	4.2	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =10mA	Fig.4, 11
				2.8		V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =10mA, T <sub>j</sub> =175°C	
Drain source breakdown voltage	V <sub>(BR)DSS</sub>	V	1200			V <sub>GS</sub> =0V, I <sub>D</sub> =100uA	
Gate source leakage current	I <sub>GSS</sub>	nA			200	V <sub>GS</sub> =18V, V <sub>DS</sub> =0V	
Current drain source on-state resistance	R <sub>DS ON</sub>	mΩ		30	50	V <sub>GS</sub> =18V, I <sub>D</sub> =30A, T <sub>j</sub> =25°C	Fig.5, 6, 7
				50		V <sub>GS</sub> =18V, I <sub>D</sub> =30A, T <sub>j</sub> =175°C	
Internal gate resistance	R <sub>g</sub>	Ω		2.1		f=1MHz, V <sub>AC</sub> =25mV	
Transconductance	g <sub>fs</sub>	S		20		V <sub>DS</sub> =20V, I <sub>D</sub> =30A, T <sub>j</sub> =25°C	Fig.4
				18.5		V <sub>DS</sub> =20V, I <sub>D</sub> =30A, T <sub>j</sub> =175°C	

**■Dynamic Electrical Characteristics** (Tc=25°C unless otherwise specified )

PARAMETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Input capacitance	C <sub>iss</sub>	pF		2995		V <sub>DS</sub> =1000V, V <sub>GS</sub> =0V, T <sub>j</sub> =25°C, f=1MHz, V <sub>AC</sub> =25mV	Fig.13, 14
Output capacitance	C <sub>oss</sub>			119			
Reverse capacitance	C <sub>rss</sub>			11.4			
Coss stored energy	E <sub>oss</sub>	uJ		130			Fig.15
Gate source charge	Q <sub>gs</sub>	nC		24		V <sub>DS</sub> =800V, V <sub>GS</sub> =-5/18V, I <sub>D</sub> =30A	Fig.12
Gate drain charge	Q <sub>gd</sub>			58			
Gate charge	Q <sub>g</sub>			127			

**■Switching Characteristics** (Tc=25°C unless otherwise specified )

PARAMETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Turn on switching energy	E <sub>on</sub>	uJ		685		V <sub>DD</sub> =800V, V <sub>GS</sub> =-5/+18V, I <sub>D</sub> =30A, R <sub>g</sub> =2.5Ω, L=200uH	Fig. 19, 20
Turn off switching energy	E <sub>off</sub>			78			
Turn on delay time	t <sub>d(on)</sub>	ns		60		V <sub>DD</sub> =800V, V <sub>GS</sub> =-5/+18V, I <sub>D</sub> =30A, R <sub>g</sub> =2.5Ω, L=200uH	Fig.21
Rise time	t <sub>r</sub>			140			
Turn off delay time	t <sub>d(off)</sub>			50			
Fall time	t <sub>f</sub>			42			

### ■Body diode characteristics (T<sub>c</sub>=25°C unless otherwise specified)

PARAMETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Diode forward voltage	V <sub>SD</sub>	V		3.5		V <sub>GS</sub> =-5V, I <sub>SD</sub> =15A, T <sub>j</sub> =25°C	Fig.8
				3.0		V <sub>GS</sub> =0V, I <sub>SD</sub> =15A, T <sub>j</sub> =175°C	Fig.9
Continuous diode forward current	I <sub>s</sub>	A		68		T <sub>c</sub> =25°C	
Reverse recovery time	t <sub>rr</sub>	nS		34		V <sub>R</sub> =800V, V <sub>GS</sub> =-5V, I <sub>SD</sub> =30A, di/dt=1428A/uS	
Reverse recovery charge	Q <sub>rr</sub>	nC		205			
Peak reverse recovery current	I <sub>rrm</sub>	A		14			

### ■Thermal Characteristics (T<sub>a</sub>=25°C Unless otherwise specified)

PARAMETER	SYMBOL	UNIT	Typ.
Thermal resistance	R <sub>θJ-C</sub>	°C/W	0.45

### ■Typical Characteristics

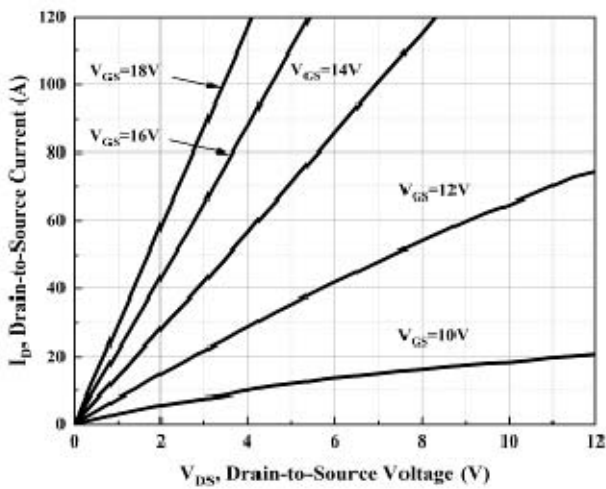


Figure 1. Output Characteristics T<sub>j</sub> = -55°C

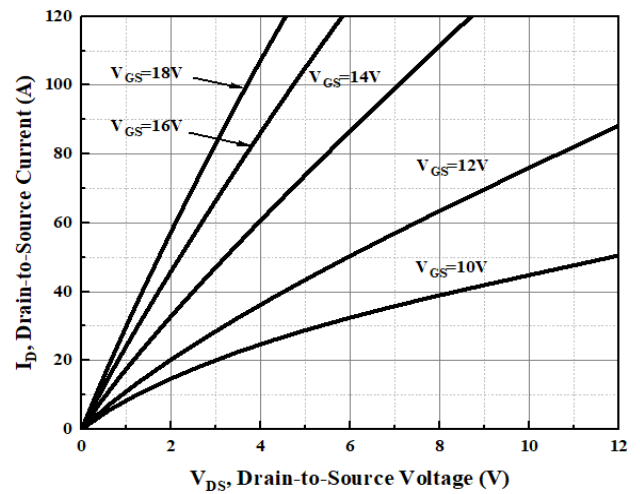


Figure 2. Output Characteristics T<sub>j</sub> = 25°C

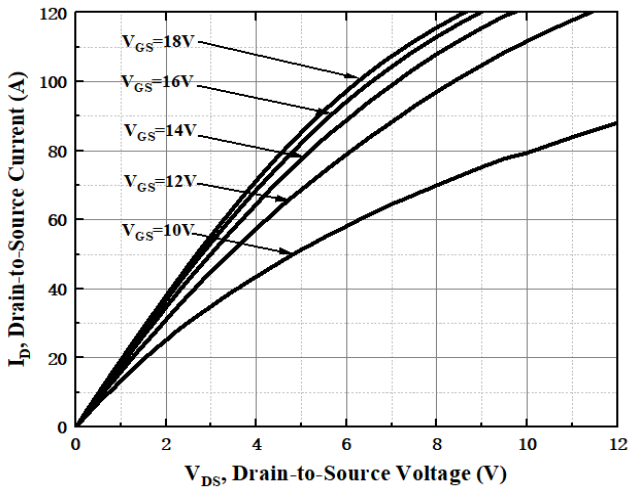


Figure 3. Output Characteristics  $T_j = 175^\circ\text{C}$

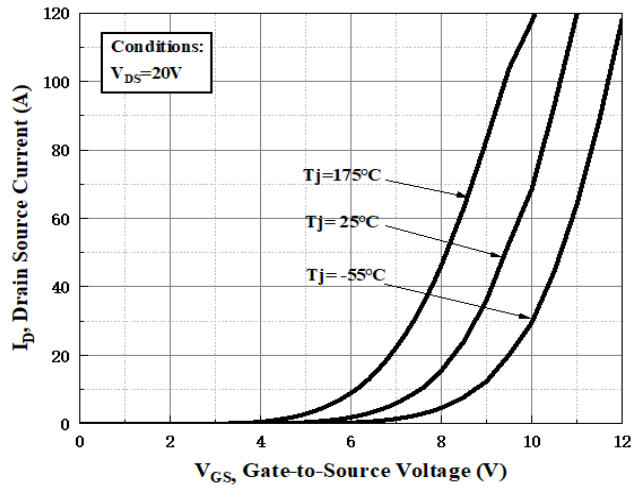


Figure 4. Transfer Characteristics for Various Junction Temperature

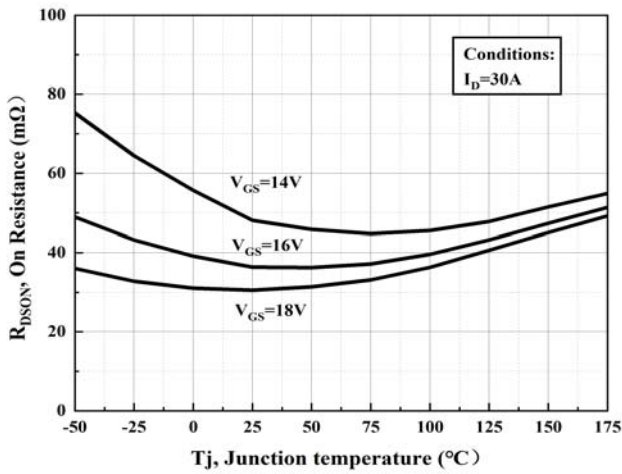


Figure 5. On-resistance vs. Temperature for Various Gate Voltage

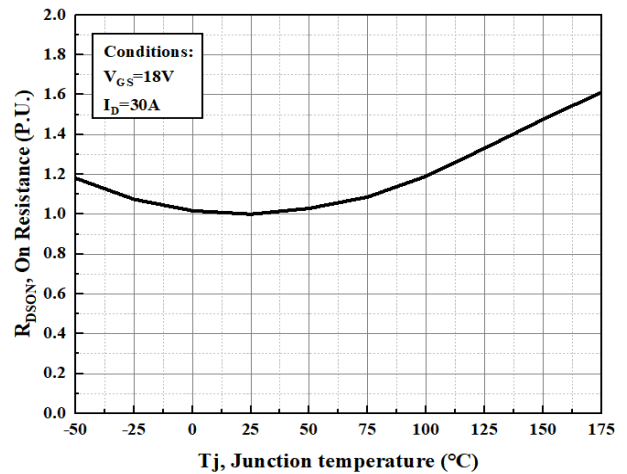


Figure 6. Normalized on-resistance vs. Temperature

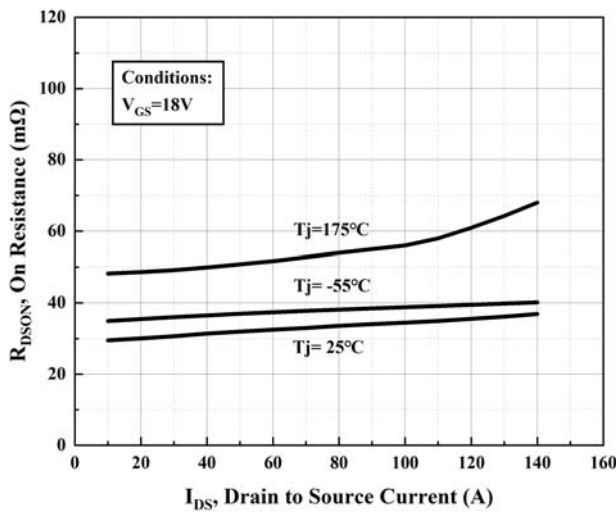


Figure 7. On-resistance vs. Drain Current

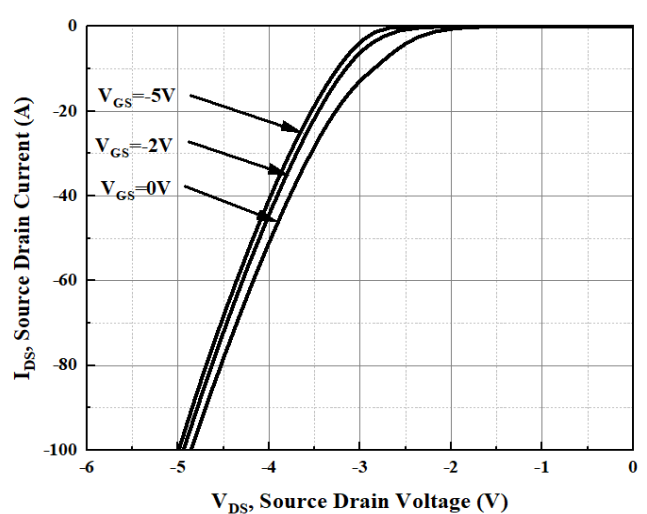


Figure 8. Body Diode Characteristic at  $T_j = 25^\circ\text{C}$

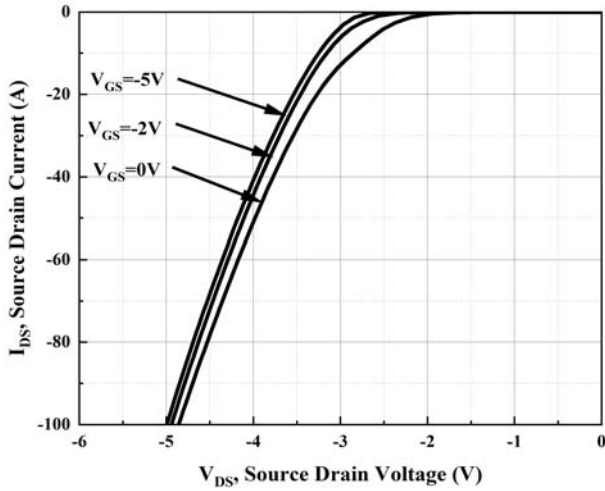


Figure 9. Body Diode Characteristic

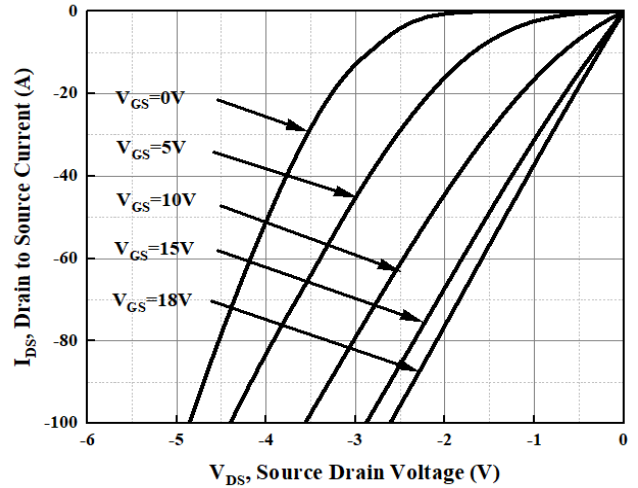


Figure 10. 3<sup>rd</sup> quadrant Characteristic at Tj= 25 °C

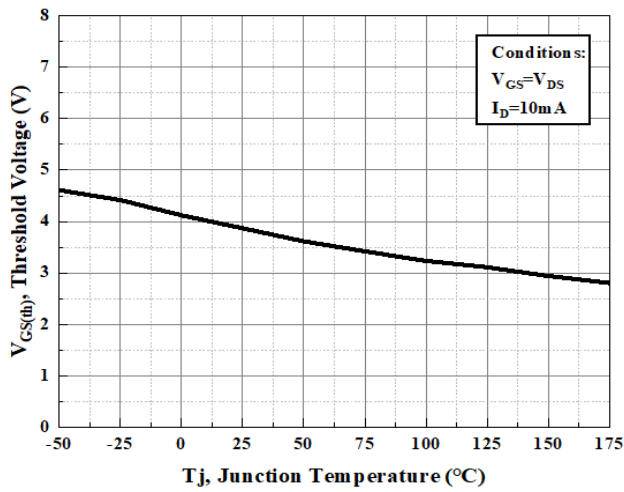


Figure 11. Threshold Voltage vs. Temperature

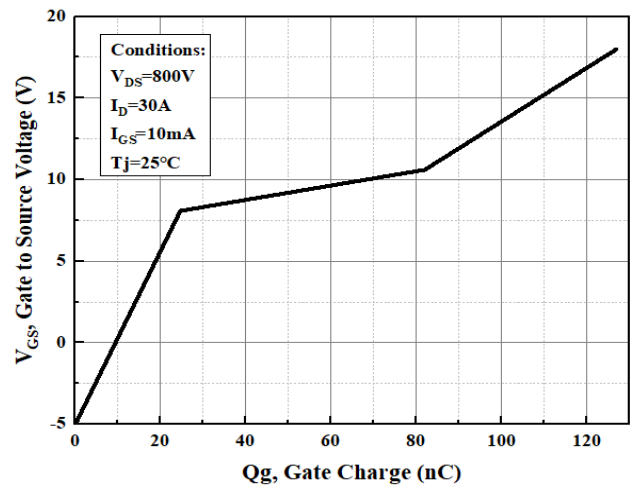


Figure 12. Gate Charge Characteristic

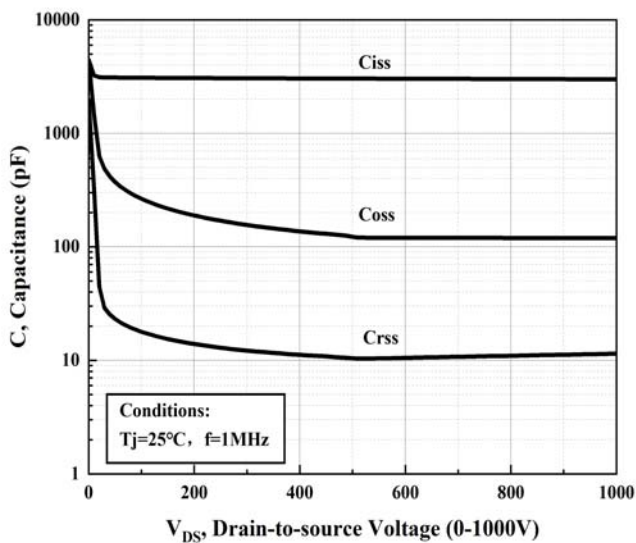


Figure 13. Capacitances vs. Drain Source Voltage (0-1000V)

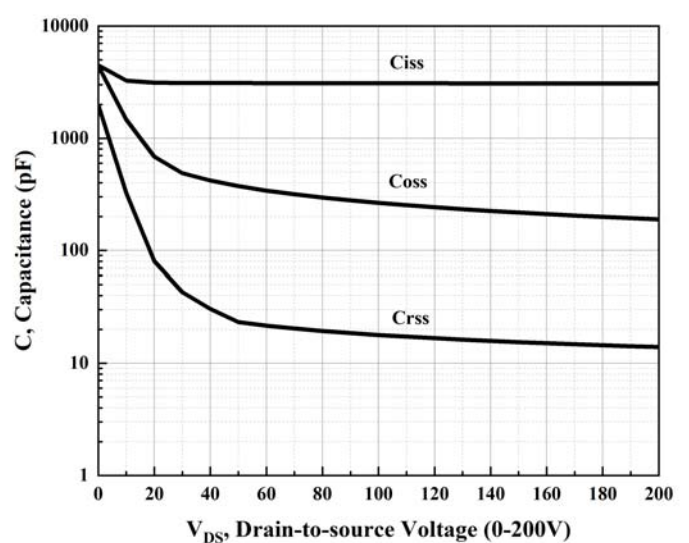


Figure 14. Capacitances vs. Drain Source Voltage (0-200V)

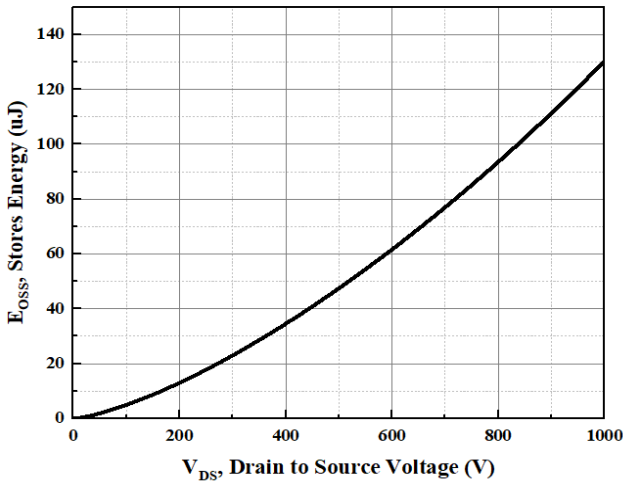


Figure 15. Output Capacitor Stored Energy

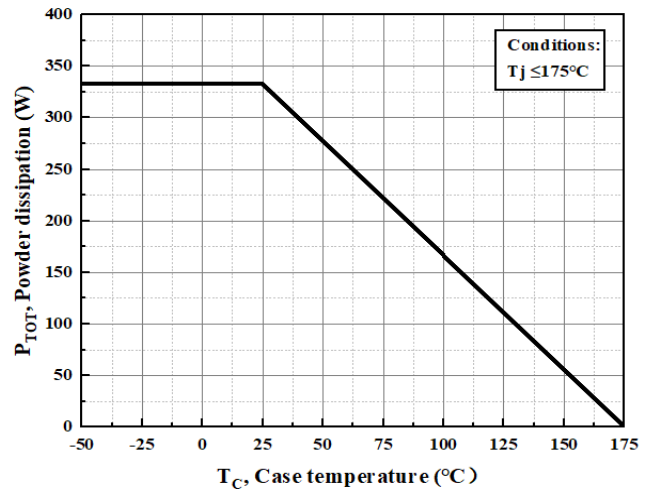


Figure 16. Maximum Power Dissipation Derating vs. Case Temperature

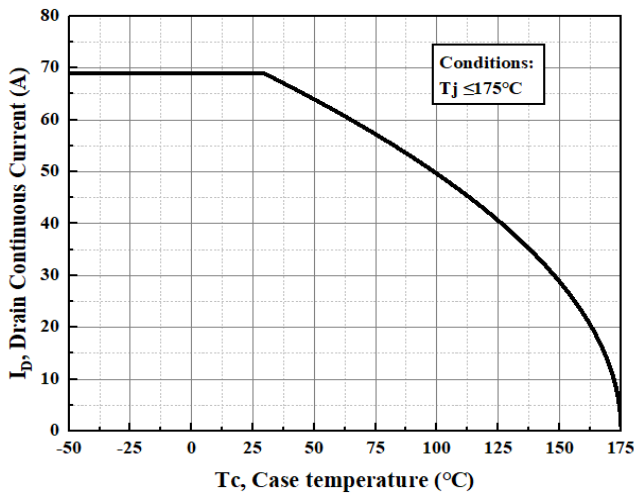


Figure 17. Continuous Drain Current Derating vs. Case Temperature

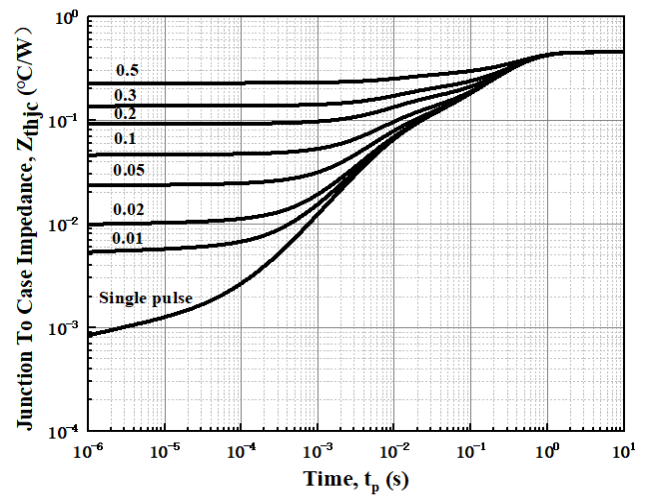


Figure 18. Transient Thermal Impedance (Junction - Case)

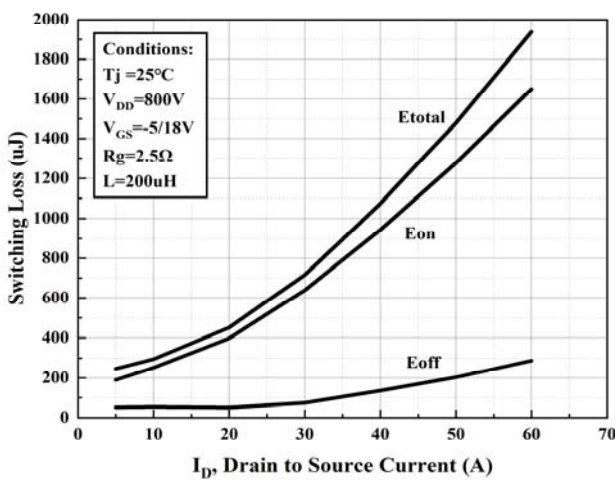


Figure 19. Clamped Inductive Switching Energy vs. Drain Current

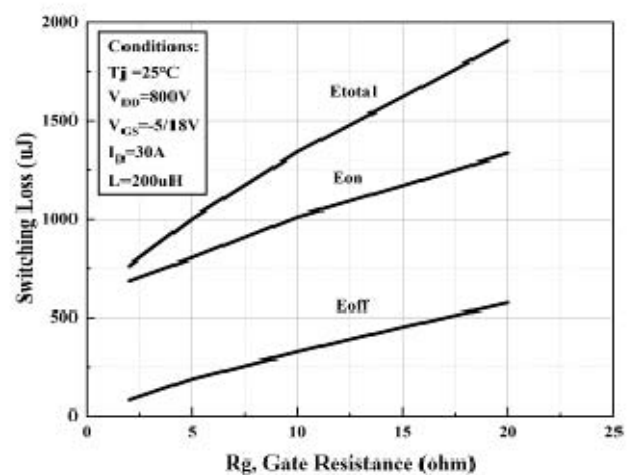


Figure 20. Clamped Inductive Switching Energy vs.  $R_g$

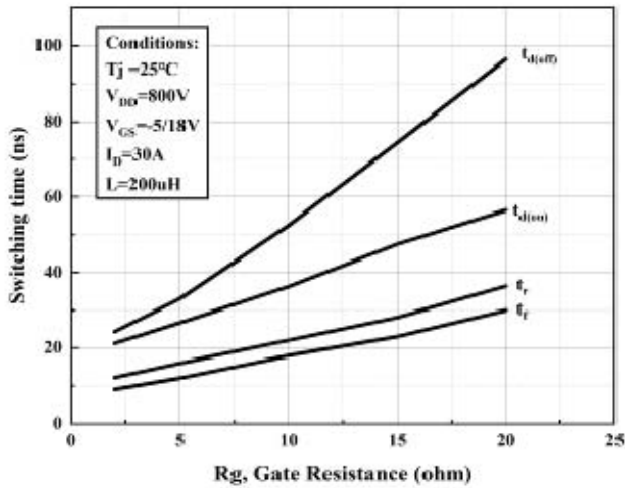


Figure 21. Switching Times vs. Rg

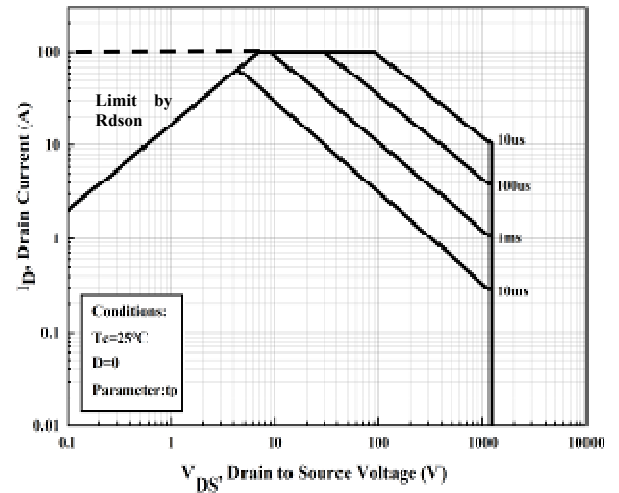


Figure 22. Safe Operating Area

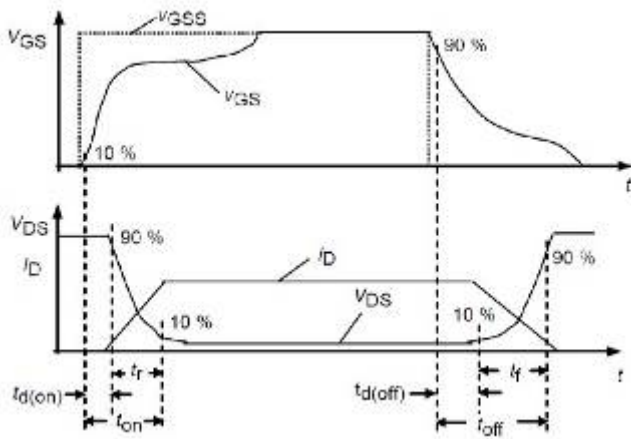


Figure 23. Switching Times Definition

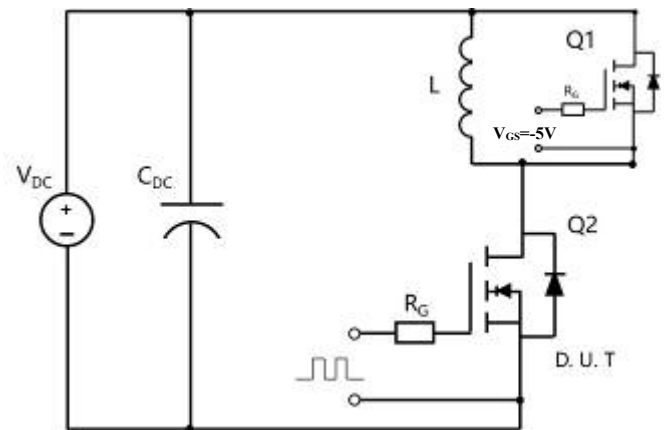
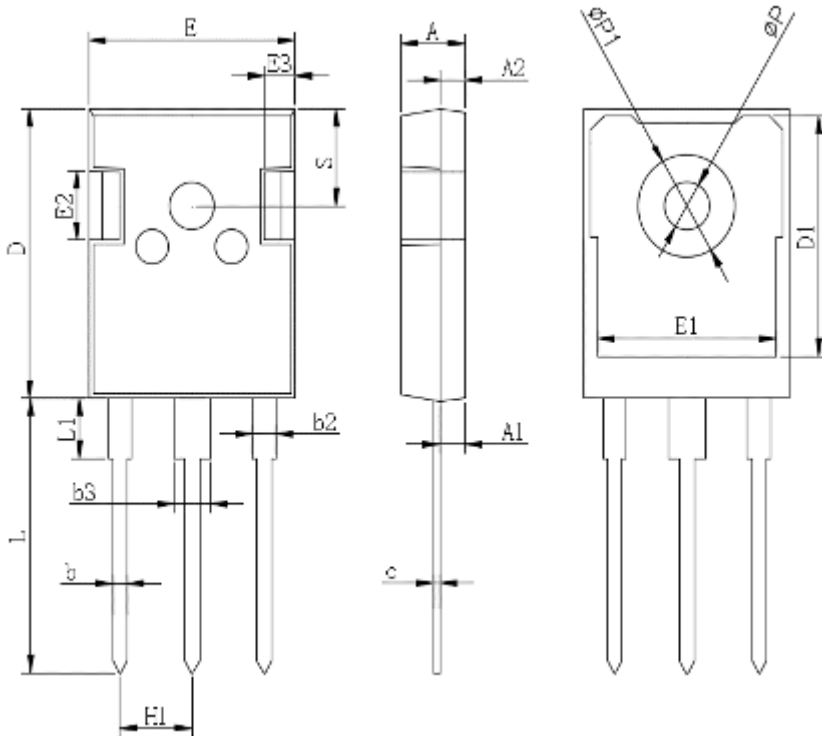


Figure 24. Clamped Inductive Switching Waveform Test Circuit

## ■Outline Dimensions

TO-247AB



TO-247AB		
Dim	Min	Max
A	4.80	5.20
A1	2.21	2.61
A2	1.85	2.15
b	1.0	1.4
b2	1.91	2.21
C	0.5	0.7
D	20.70	21.30
D1	16.25	16.85
E	15.50	16.10
E1	13.0	13.6
E2	4.80	5.20
E3	2.30	2.70
L	19.62	20.22
L1	-	4.30
$\Phi P$	3.40	3.80
$\Phi P1$	-	7.30
S	6.15TYP	
H1	5.44TYP	
b3	2.80	3.20





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